# 2SB1434

### Silicon PNP epitaxial planer type

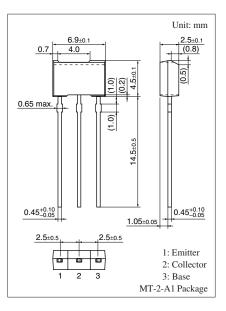
For low-frequency output amplification Complementary to 2SD2177

#### Features

- $\bullet$  Low collector-emitter saturation voltage  $V_{CE(sat)}$
- Allowing supply with the radial taping

Parameter	Symbol	Rating	Unit				
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-50	V				
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-50	V				
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	-5	V				
Collector current	I <sub>C</sub>	-2	А				
Peak collector current	I <sub>CP</sub>	-3	А				
Collector power dissipation *	P <sub>C</sub>	1	W				
Junction temperature	Tj	150	°C				
Storage temperature	T <sub>stg</sub>	-55 to +150	°C				





Note) \*: Print circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

#### Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	$I_{\rm C} = -10 \ \mu A, \ I_{\rm E} = 0$	-50			V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{\rm C} = -1 \text{ mA}, I_{\rm B} = 0$	-50			V
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	$I_E = -10 \ \mu A, \ I_C = 0$	-5			V
Collector-base cutoff current (Emitter open)	I <sub>CBO</sub>	$V_{CB} = -20 \text{ V}, I_E = 0$			- 0.1	μΑ
Forward current transfer ratio	h <sub>FE1</sub> *2	$V_{CE} = -2 V, I_C = -200 mA$	120		340	_
	h <sub>FE2</sub> *1	$V_{CE} = -2 V, I_C = -1 A$	60			
Collector-emitter saturation voltage *1	V <sub>CE(sat)</sub>	$I_{C} = -1 A, I_{B} = -50 mA$		- 0.2	- 0.3	V
Base-emitter saturation voltage *1	V <sub>BE(sat)</sub>	$I_{C} = -1 \text{ A}, I_{B} = -50 \text{ mA}$		- 0.85	-1.20	V
Transition frequency	f <sub>T</sub>	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		110		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		40	60	pF
(Common base, input open circuited)						

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

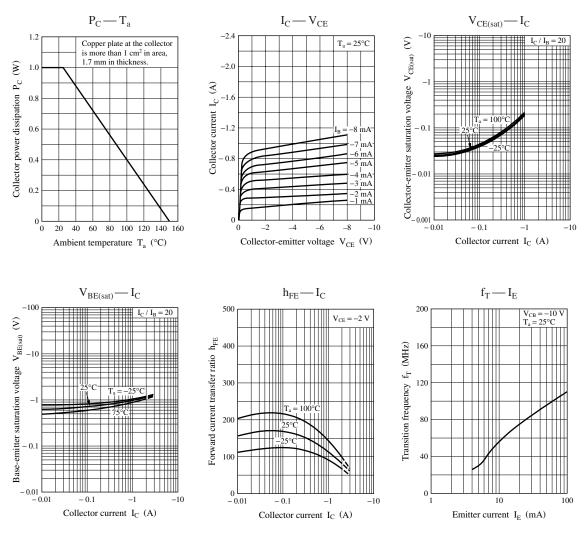
2. \*1: Pulse measurement

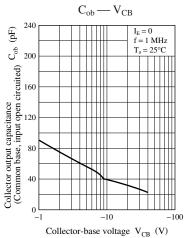
\*2: Rank classification

Rank	R	S	No-rank
h <sub>FE1</sub>	120 to 240	170 to 340	120 to 340

Product of no-rank is not classification is not marked.

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